

## X - Ray Diffraction (XRD)

### Sample Requirement:-

1. Solid Sample - 2 gms.

### Applications :-

1. To identify Crystalline Phase.
2. To measure % Crystallinity.
3. Nature of Sample Crystalline or Amorphous.
4. To identify Inorganic Compounds.



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Send your Enquiries



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## Anchor Scan Parameters

4

Raw Data Origin:	XRD measurement (*.XRDML)
Scan Axis:	Gonio
Start Position [ $^{\circ}2\theta$ .]:	4.5100
End Position [ $^{\circ}2\theta$ .]:	79.9700
Step Size [ $^{\circ}2\theta$ .]:	0.0200
Scan Step Time [s]:	0.5000
Scan Type:	Continuous
Offset [ $^{\circ}2\theta$ .]:	0.0000
Divergence Slit Type:	Fixed
Divergence Slit Size [ $^{\circ}$ ]:	1.0000
Specimen Length [mm]:	10.00
Receiving Slit Size [mm]:	0.7600
Measurement Temperature [ $^{\circ}\text{C}$ ]:	25.00
Anode Material:	Cu
K-Alpha1 [ $\text{\AA}$ ]:	1.54060
K-Alpha2 [ $\text{\AA}$ ]:	1.54443
K-Beta [ $\text{\AA}$ ]:	1.39225
K-A2 / K-A1 Ratio:	0.50000
Generator Settings:	40 mA, 45 kV
Diffractometer Type:	0000000011141934
Diffractometer Number:	0
Goniometer Radius [mm]:	240.00
Dist. Focus-Diverg. Slit [mm]:	100.00
Incident Beam Monochromator:	No
Spinning:	No

## Graphics



